

stub protruding widthwise from the pattern line, said method comprising: forming an auxiliary cut-and-removed portion by partly cutting and removing the at least one stub so that the at least one stub is made apparently longer.

2. (Amended) A matching-circuit impedance adjusting method according to Claim 1, further comprising:

A based on a relationship between cutting-out amounts for partly cutting out the at least one stub of the pattern line and impedances of the matching circuit, and a relationship between cutting-and-removing amounts of the auxiliary cut-and-removed portion for partly cutting and removing the at least one stub and the impedances of the matching circuit, determining a cutting-out amount, a cutting-and-removing amount, or the cutting-out amount and the cutting-and-removing amount, for adjusting the impedance of the matching circuit to a target value by simulation or by a comparison operation of an impedance measured value with information in a database; and

based on the cutting-out amount, the cutting-and-removing amount, or the cutting-out amount and the cutting-and-removing amount, of the at least one stub determined by the simulation or by the comparison operation of the impedance measured value with the information in the database, partly cutting out or cutting and removing the at least one stub, so that the impedance of the matching circuit is adjusted to the target value.

3. (Amended) A matching-circuit impedance adjusting method according to Claim 1, wherein said partly cutting and removing of the at least one stub to form the auxiliary cut-and-removed portion comprises forming at least one slit along a widthwise direction of the at least one stub.

4. (Amended) A matching-circuit impedance adjusting method according to Claim 3, wherein the at least one slit is three or more slits in the at least one stub of the pattern line so that the three or more slits are formed as comb-teeth-like cuts.

5. (Amended) A matching-circuit impedance adjusting method according to Claim 3, wherein the at least one slit is three or more slits in the at least one stub of the pattern line so that the three or more slits are formed as staggered cuts.

6. (Amended) A matching-circuit impedance adjusting method according to Claim 1, wherein said partly cutting and removing of the at least one stub of the pattern line to form the auxiliary cut-and-removed portion comprises forming a cut-out along a widthwise direction of the at least one stub of the pattern line.

7. (Amended) A matching-circuit impedance adjusting method according to Claim 1, wherein said partly cutting and removing of the at least one stub of the pattern line to form the auxiliary cut-and-removed portion comprises forming a hook-type slit in the at least one stub of the pattern line.

8. (Amended) A matching-circuit impedance adjusting method according to Claim 1, wherein a cutting-out amount, a cutting-and-removing amount, or the cutting-out amount and cutting-and-removing amount, of each of the at least one stub of the pattern line are different from one another.

9. (Amended) A matching-circuit impedance adjusting method according to Claim 1, further comprising: changing a cutting-and-removing amount of the auxiliary cut-and-removed portion in a thicknesswise direction of the at least one stub of the pattern line, thereby performing the impedance adjustment.

10. (Amended) A matching-circuit impedance adjusting method according to Claim 1, wherein said forming of the auxiliary cut-and-removed portion comprises, with a recessed portion previously formed along a thicknesswise direction of the at least one stub of the pattern line,

burying an insulating resin in the recessed portion and then cutting and removing the insulating resin to form the auxiliary cut-and-removed portion.

11. (Amended) A matching-circuit impedance adjusting method according to Claim 1, further comprising: performing fine adjustment in accordance with an impedance characteristic by combining a widthwise cutting-and-removing of the at least one stub of the pattern line and a thicknesswise cutting-and-removing of the at least one stub of the pattern line.

12. (Amended) A matching-circuit impedance adjusting method according to Claim 1, further comprising: with an impedance variation amount on a Smith chart changed by a length and a width of the auxiliary cut-and-removed portion, adjusting the impedance of the matching circuit to a target value based on a phase on the impedance.

13. (Amended) A matching-circuit impedance adjusting method according to Claim 1, wherein said forming of the auxiliary cut-and-removed portion comprises partly cutting and removing the at least one stub with a laser beam.